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## (54) Polishing pad and apparatus for polishing a semiconductor wafer

(57) An apparatus for polishing a semiconductor wafer includes a polishing pad to be in contact with the semiconductor wafer; a turn table which rotates the polishing pad; and an elastic member which is arranged between the turn table and the polishing pad. The polishing pad includes a polishing layer which is made of a material having a good characteristic of slurry holding; and a support layer which is made of a rigid material having an optimum thickness to prevent the polishing layer from loosening. The polishing pad is attached to the turn table by a stretch-holding technique without adhesive bonding.

21 TURN TABLE

138 SLIERTY SUPPLY HOLE

134 135 100 SILICON WAFER
142 WAFER STABE

FIG. 1

EP 0 845 328 A3



## **EUROPEAN SEARCH REPORT**

**Application Number** EP 97 12 0892

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